

NPT1012B

Rev. V1

Features

- Optimized for Broadband Operation (DC 4 GHz)
- 25 W P3dB CW Power @ 3000 MHz
- 16 20 W P3dB CW Power from 1.0 2.5 GHz in application board with >45% Drain Efficiency
- 10 20 W P3dB CW Power from 0.03 1.0 GHz in application board with >50% Drain Efficiency
- High Efficiency from 14 to 28 V
- 4°C/W R_{TH} with T_J <200°C
- Robust up to 10:1 VSWR Mismatch at All Angles with No Device Damage at 90°C Flange
- Subject to EAR99 Export Control
- RoHS* Compliant

Applications

- Defense Communications
- Land Mobile Radio
- Avionics
- Wireless Infrastructure
- ISM
- VHF/UHF/L/S-Band Radar

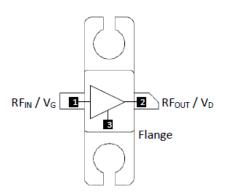
Description

The NPT1012B GaN HEMT is a power transistor optimized for DC - 4 GHz operation. This device supports CW, pulsed, and linear operation with output power levels to 25 W. This transistor is assembled in an industry standard surface mount plastic package.

Ordering Information

Part Number	Package
NPT1012B	30 slot tray

Functional Schematic



Pin Configuration

Pin#	Pin Name	Function		
1	RF _{IN} / V _G	RF Input / Gate		
2	RF _{OUT} / V _D	RF Output / Drain		
3	Flange ¹	Ground / Source		

^{1.} The flange must be connected to RF and DC ground. This path must also provide a low thermal resistance heat path.

^{*} Restrictions on Hazardous Substances, compliant to current RoHS EU directive.



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Typical CW RF Specifications: (measured in a test fixture) Freq. = 3 GHz, V_{DS} = 28 V, I_{DQ} = 225 mA, T_{C} = 25°C

Parameter	Test Conditions	Symbol	Min.	Тур.	Max.	Units
Average Output Power	3 dB Compression 1 dB Compression	43 —	44 43	_	W	
Small Signal Gain	_	G _{SS}	12	13	_	dB
Drain Efficiency	3 dB Compression	η	57	65	_	%
Output Mismatch Stress	VSWR = 10:1. all phase angles, $P_{OUT} = P_{SAT}$	Ψ	No performance degradation after test			

DC Electrical Characteristics: T_C = 25°C

Parameter	Test Conditions	Symbol	Min.	Тур.	Max.	Units
Off Characteristics						
Drain-Source Breakdown Voltage	V _{GS} = -8 V, I _D = 8 mA	V _{BDS}	100	_	_	V
Drain-Source Leakage Current	n-Source Leakage Current V_{GS} = -8 V, V_{DS} = 60 V				4	mA
On Characteristics						
Gate Threshold Voltage	V _{DS} = 28 V, I _D = 8 mA	V _T	-2.3	-1.8	-1.3	V
Gate Quiescent Voltage	V _{DS} = 28 V, I _D = 225 mA	V_{GSQ}	-2.0	-1.5	-1.0	V
On Resistance	V _{GS} = 2 V, I _D = 60 mA	R _{ON}	_	0.44	0.55	Ω
Drain Current	V_{DS} = 7 V pulsed, pulse width 300 µs 0.2% Duty Cycle, V_{GS} = 2 V	I _D	_	5.4	_	Α



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Absolute Maximum Ratings^{2,3,4}

Parameter	Absolute Maximum		
Drain Source Voltage, V_{DS}	100 V		
Gate Source Voltage, V _{GS}	-10 to 3 V		
Gate Current, I _G	40 mA		
Total Device Power Dissipation (derated above +25°C)	44 W		
Junction Temperature, T _J	+200°C		
Operating Temperature	-40°C to +85°C		
Storage Temperature	-65°C to +150°C		

^{2.} Exceeding any one or combination of these limits may cause permanent damage to this device.

Thermal Characteristics⁵

Parameter	Test Conditions	Symbol	Typical	Units
Thermal Resistance	V _{DS} = 28 V, T _J = 180°C	$R_{\theta JC}$	4.0	°C/W

^{5.} Junction temperature (T_J) measured using IR Microscopy. Case temperature measured using thermocouple embedded in heat-sink.

Handling Procedures

Please observe the following precautions to avoid damage:

Static Sensitivity

Gallium Nitride Circuits are sensitive to electrostatic discharge (ESD) and can be damaged by static electricity. Proper ESD control techniques should be used when handling these MM Class A, CDM Class IV, HBM Class 1B devices.

^{3.} MACOM does not recommend sustained operation near these survivability limits.

^{4.} Operating at nominal conditions with $T_J \le 200$ °C will ensure MTTF > 1 x 10^6 hours.



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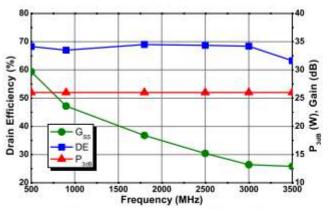


Figure 1 - Typical CW Performance in Load-Pull, V_{DS} = 28V, I_{DQ} = 225mA

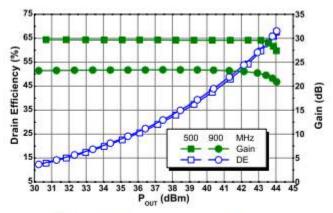


Figure 2 - Typical CW Performance¹ in Load-Pull, V_{DS} = 28V, I_{DQ} = 225mA



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Load-Pull Data, Reference Plane at Device Leads: V_{DS} = 28 V, I_{DQ} = 225 mA, T_C = 25°C

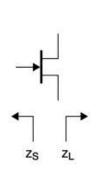
Table 1: Optimum Impedance Characteristics for CW Gain, Drain Efficiency, and Output Power Performance

Frequency (MHz)	V _{DS} (V)	Z _S (Ω)	Z _L (Ω)	P _{SAT} (W)	GSS (dB)	Drain Efficiency @ P _{SAT} (%)
500 ⁶	14	7.0 + j8.2	8.6 + j7.4	12	27.8	76
500 ⁶	22	7.0 + j8.2	9.7 + j11.3	21	29.2	74
500 ⁶	28	7.0 + j8.2	9.7 + j14.1	26	29.7	68
900 ⁶	14	5.8 + j3.1	6.8 + j4.7	12	22.4	74
900 ⁶	22	5.8 + j3.1	9.6 + j5.3	24	23.3	74
900 ⁶	28	5.8 + j3.1	9.8 + j7.8	26	23.6	67
1800	28	3.5 - j3.6	6.9 + j2.0	26	18.4	69
2500	14	3.9 - j7.5	6.2 - j8.0	13	13.7	70
2500	22	4.8 - j7.0	5.5 - j4.1	19	14.9	69
2500	28	4.8 - j7.0	5.5 - j4.1	26	15.2	69
3000	28	5.3 - j8.8	5.3 - j6.4	26	13.2	66
3500	28	5.0 - j14.5	7.0 - j9.5	26	12.9	63

^{6. 500} MHz and 900 MHz Load-Pull data collected using a 4.7 Ω resistor in the RF path added for stability.

Impedance Reference

Z_S and Z_L vs. Frequency



Zs is the source impedance presented to the device. ZL is the load impedance presented to the device.

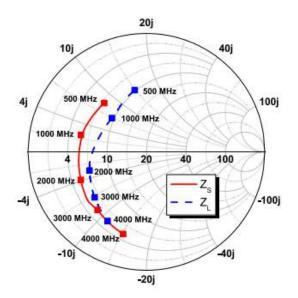
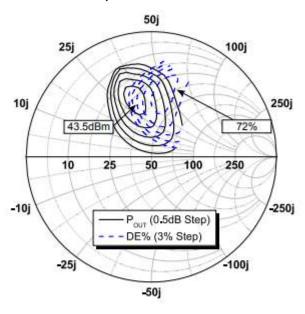


Figure 3 - Optimum Impedances for CW Performance, V_{DS} = 28V



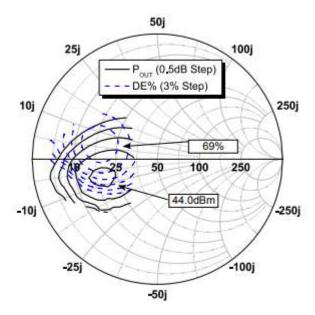
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25j 100j 250j 100j 250j 100 250 -250j -250j -250j -250j -250j

Figure 4 - Load-Pull Contours 1, 500MHz, P_{IN} = 14.5dBm, Z_S = 7.0 + j8.2 Ω

Figure 5 - Load-Pull Contours¹, 900MHz, $P_{IN} = 21.0dBm$, $Z_S = 5.8 + j3.1 \Omega$



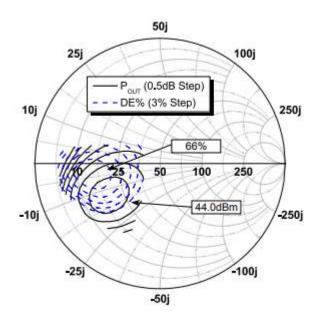
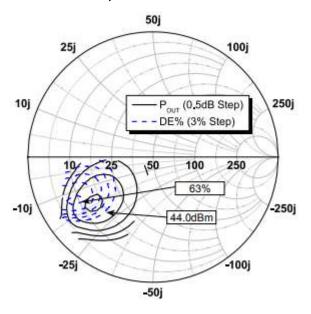


Figure 6 - Load-Pull Contours, 1800MHz, P_{IN} = 26.5dBm, Z_S = 3.5 - j3.6 Ω

Figure 7 - Load-Pull Contours, 2500MHz, P_{IN} = 29.4dBm, Z_S = 4.8 - j7.0 Ω



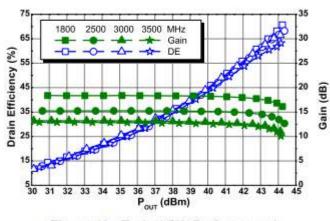
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25j 100j -- DE% (0.5dB Step) 250j -- DE% (3% Step) -- 250j -- 250j -- 250j -- 250j

Figure 8 - Load-Pull Contours, 3000MHz, P_{IN} = 31.7dBm, Z_S = 5.3 - j8.8 Ω

Figure 9 - Load-Pull Contours, 3500MHz, P_{IN} = 33.5dBm, Z_S = 5.0 - j14.5 Ω



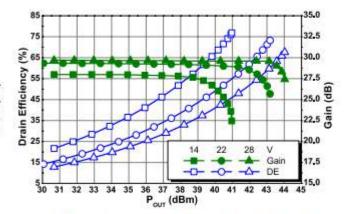


Figure 10 - Typical CW Performance in Load-Pull

Figure 11 - Typical CW Performance¹ Over Voltage in Load-Pull, 500MHz



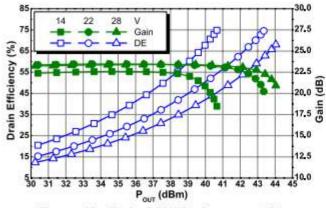


Figure 12 - Typical CW Performance¹ Over Voltage in Load-Pull, 900MHz

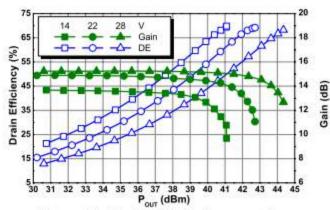


Figure 13 - Typical CW Performance Over Voltage in Load-Pull, 2500MHz

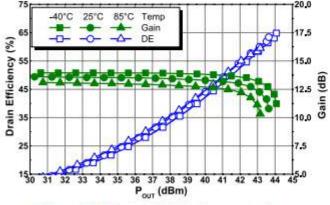


Figure 14 - Typical CW Performance Over Temperature in Nitronex Test Fixture, 3000MHz

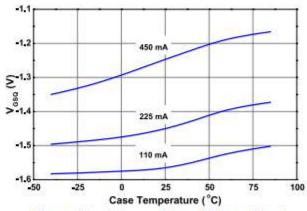


Figure 15 - Quiescent Gate Voltage (V_{GSQ})
Required to Reach I_{DQ} as a Function of
Case Temperature, V_{DS} = 28V

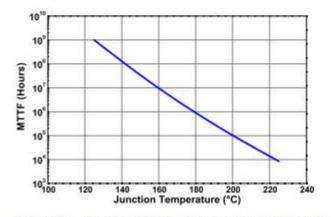


Figure 16 - MTTF of NRF1 Devices as a Function of Junction Temperature

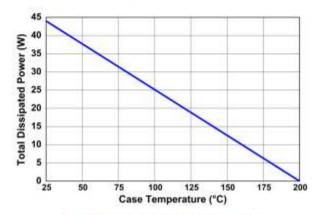
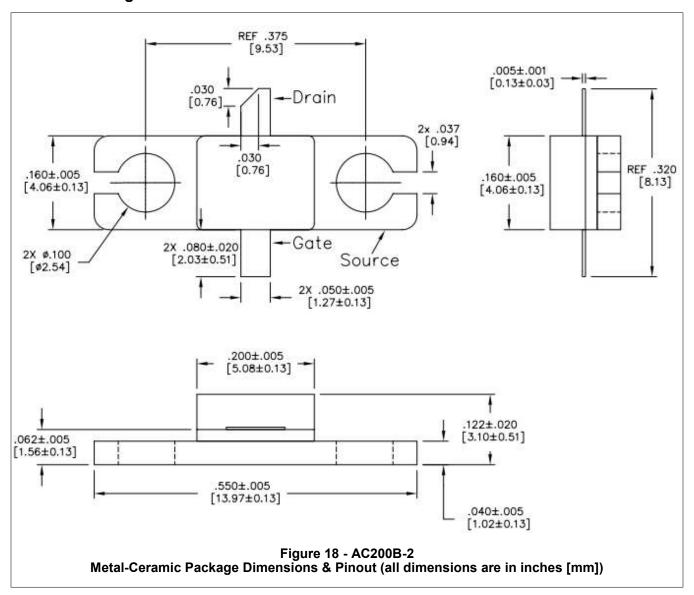


Figure 17 - Power Derating Curve



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Outline Drawing





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